

Scanning Force Microscopy: With Applications to Electric, Magnetic, and Atomic Forces (Oxford Series in Optical and Imaging Sciences)

Dror Sarid



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Since its invention in 1982, scanning tunneling microscopy (STM) has enabled users to obtain images reflecting surface electronic structure with atomic resolution. This technology has proved indispensable as a characterization tool with applications in surface physics, chemistry, materials science, bio-science, and data storage media. It has also shown great potential in areas such as the semiconductor and optical quality control industries. *Scanning Force Microscopy, Revised Edition* updates the earlier edition's survey of the many rapidly developing subjects concerning the mapping of a variety of forces across surfaces, including basic theory, instrumentation, and applications. It also includes important new research in STM and a thoroughly revised bibliography. Academic and industrial researchers using STM, or wishing to know more about its potential, will find this book an excellent introduction to this rapidly developing field.

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